Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/729,655	SHIEH, SHIUH-AN	SHIEH, SHIUH-AN	
Examiner	Art Unit		
Tai T. Nguyen	2632		

SEARCHED					
Class	Subclass	Date	Examiner		
340	561	2/28/2006	TN		
340	66	2/28/2006	TN		
340	667	2/28/2006	TN		
340	668	2/28/2006	TN		
701	45	2/29/2006	TN		
701	46	2/29/2006	TN		
701	47	2/29/2006	TN		

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
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SEARCH I (INCLUDING SEAR)
	DATE	EXMR
EAST SEARCH	2/28/2006	TN
CONSULT WITH BEN LEE	2/29/2006	TN
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